

<b>Notice of References Cited</b>	Application/Control No. 10/022,438	Applicant(s)/Patent Under Reexamination STOLTZ, ALLISON	
	Examiner Beth Van Doren	Art Unit 3623	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0059093	05-2002	Barton et al.	705/10
*	B	US-6,912,502	06-2005	Buddle et al.	705/1
*	C	US-6,029,144	02-2000	Barrett et al.	705/30
*	D	US-2001/0027389	10-2001	Beverina et al.	703/22
*	E	US-2003/0033191	02-2003	Davies et al.	705/10
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Alberts, Christopher, et al., "An Introduction to the OCTAVE Method", <a href="http://www.cert.org/octave/methodintro.html">www.cert.org/octave/methodintro.html</a> , 01/30/2001 [retrieved 05/15/06], pages 1-11, retrieved from: Google.com.
	V	Burns, Jacob, et al., "NASA Risk Assessment and Management Roadmap", University of VA Capston Conference, 04/2001 [retrieved 05/15/06], pages 183-188, retrieved from: Google.com.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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